

CPE 323

Intro to Embedded Computer Systems

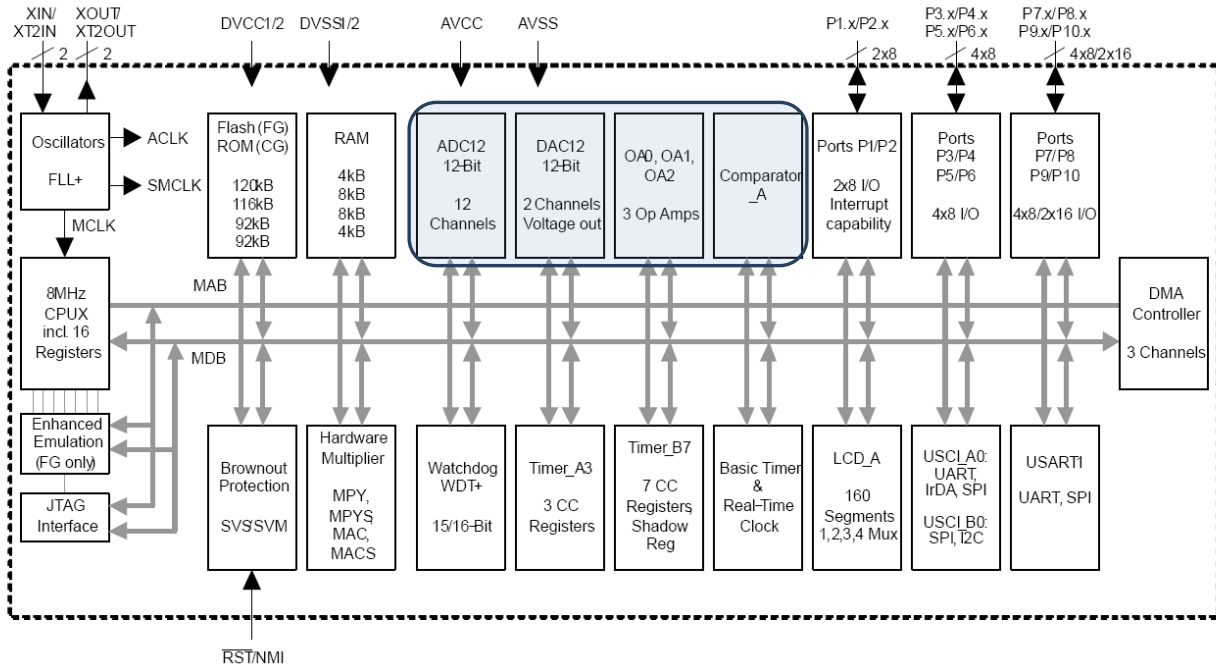
Analog-to-Digital Conversion

Aleksandar Milenkovic

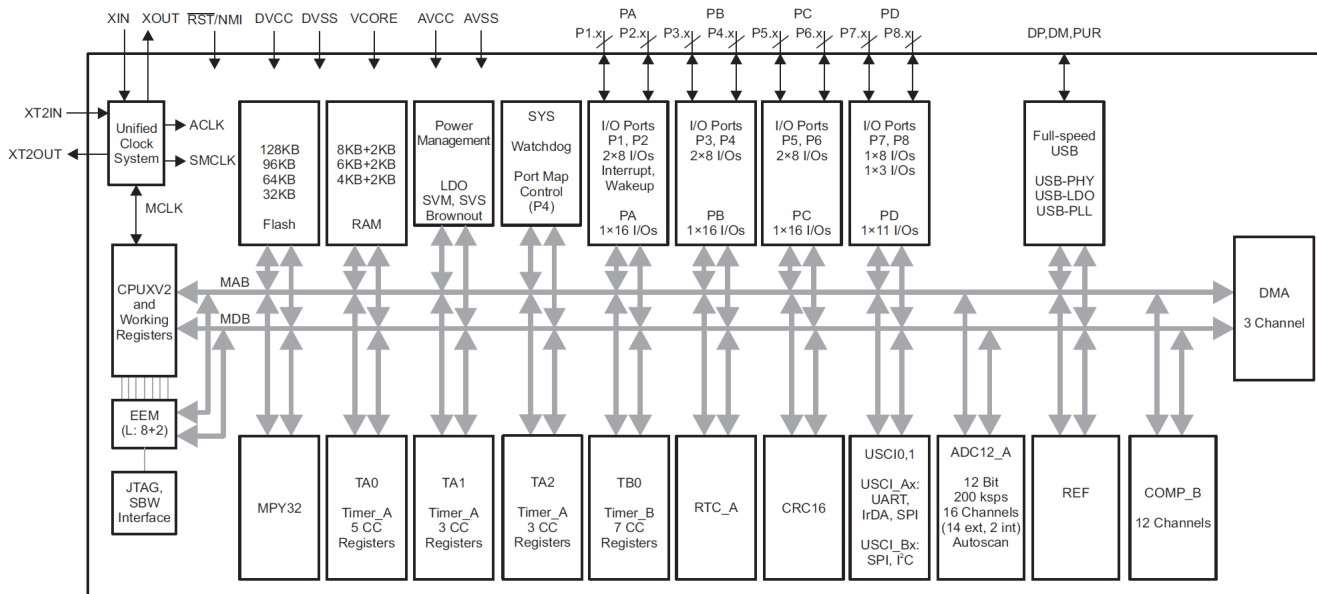
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MSP430FG4618 Block Diagram



MSP430F5529 Block Diagram



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Figure 1-1. Functional Block Diagram – MSP430F5529IPN, MSP430F5527IPN, MSP430F5525IPN, MSP430F5521IPN

Interfacing Physical World:

From Analog Signals to Digital Values

- Sensors/Transducers
 - convert physical quantity into an electrical signals
- Signal Conditioning
 - isolation from dangerous voltages due to static discharges
 - amplification of signals
 - bandwidth limiting: filters
- Analog-to-Digital Converters
 - convert analog signals to digital values

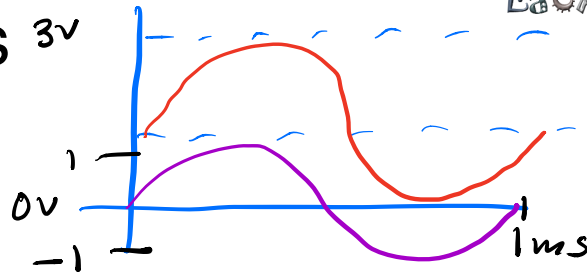
System View: From Input Analog Voltage to Bits

ADC Modules

- Analog Multiplexer
- Sample-and-hold
- AD Conversion Core
- Buffers

Definitions

$$V_{LSB} = \frac{V_{FS}}{2^n}$$



- Resolution
- Accuracy
- Transfer Function
- Aperture Time / *sample time*
- Conversion Time — *time the core needs to produce digital counter part.*
- Sampling Frequency — *How many samples you want to get.*

↳ $2 \times$ highest harmonic.

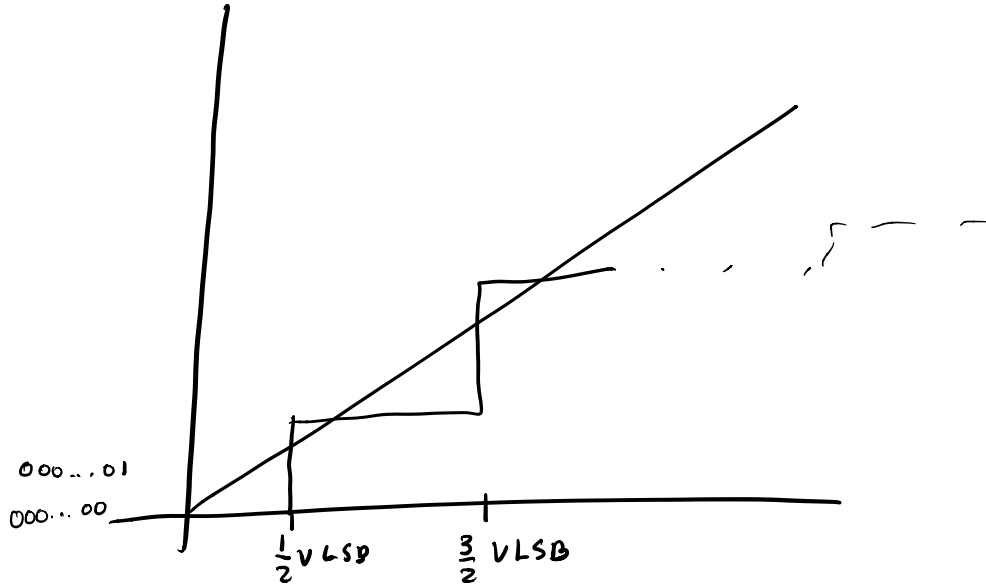
$$y = \sin(2\pi \cdot f \cdot t)$$

$$f = \frac{1}{1\text{ms}} = 1,000\text{Hz}$$

$$\text{Input} = 1.5(1 + \sin(2\pi f t))$$

$$f = 1,000\text{Hz}$$

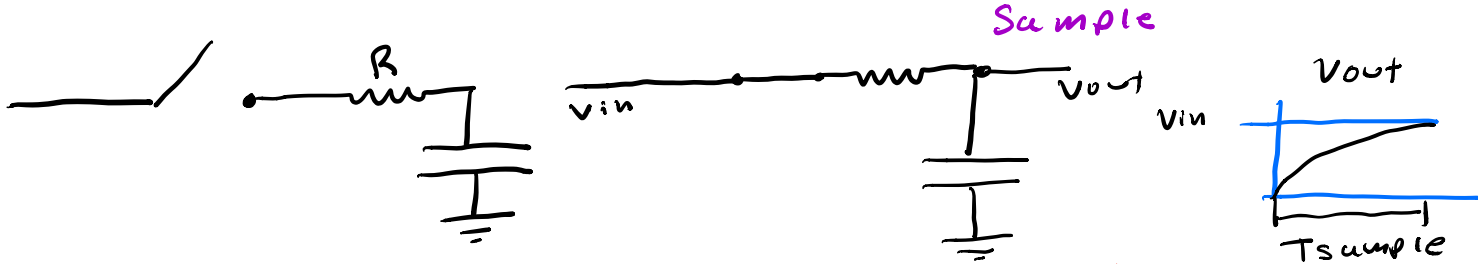
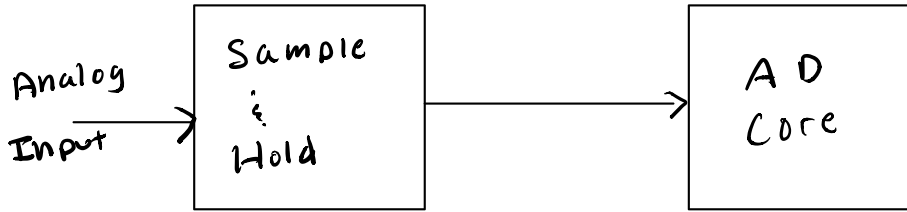
AD Transfer Function



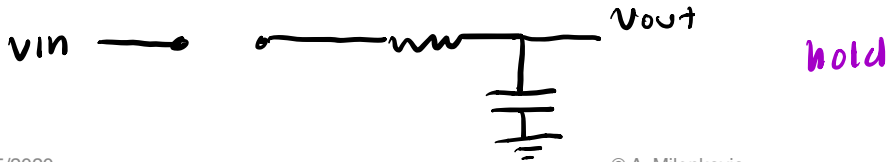
Input Analog MUX



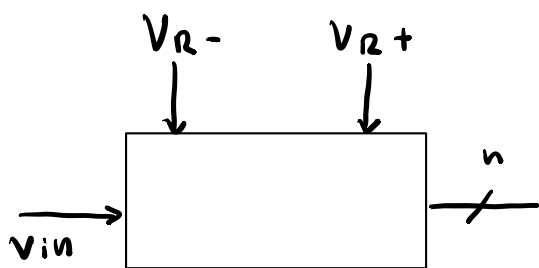
Sample&Hold



Sample time = Acquisition time



ADC Core



n bit value

Fullscale voltage

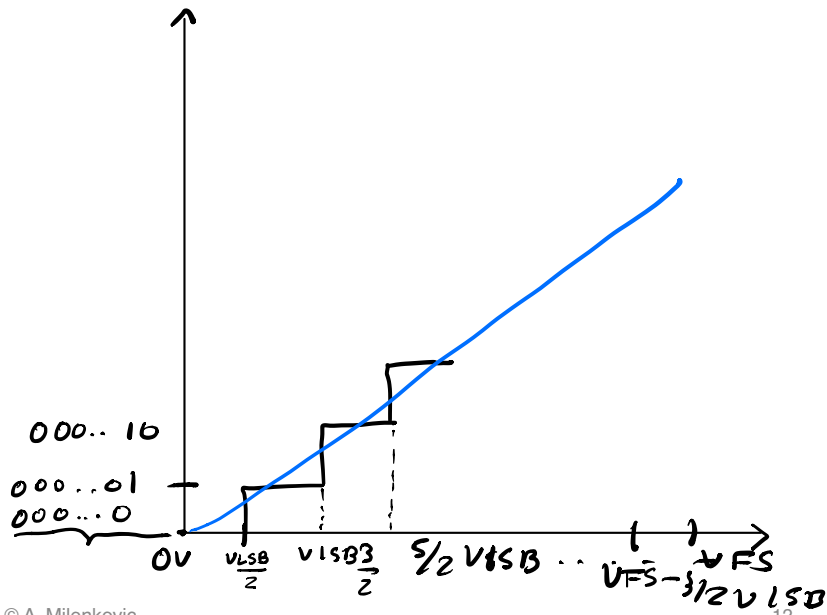
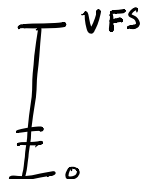
$$N_{ADC} = (2^n - 1)$$

$$V_{FS} = V_{R+} - V_{R-}$$

$$\frac{V_{in} - V_{R-}}{V_{R+} - V_{R-}}$$

$$V_R = V_{LSB} = \frac{V_{FS}}{2^n}$$

resolution voltage

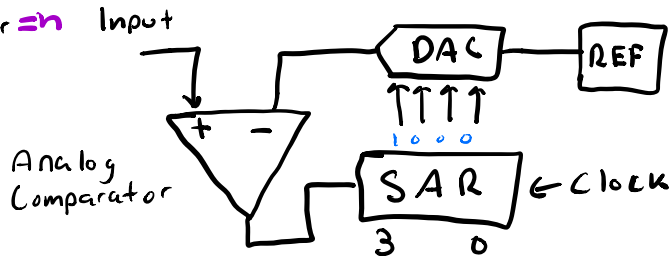
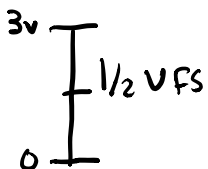


Successive Approximation Register (SAR) ADC Core

Example:

4-bit-converter $n=4$ Input

$V_{FS} = 3V$



$$V_R = \frac{V_{FS}}{2^n} = \frac{3V}{2^4}$$

$$V_R = 0.1875V$$

Input $> V_{DAC}$

$\Rightarrow 1$
Otherwise
 $\Rightarrow 0$

1001

Step = # bits

- Step 1: SAR: 1000 $\Rightarrow V_{DAC} = 8 \cdot V_{LSB} = 1.5V$

$V_{in} > V_{DAC} \Rightarrow$ keep 1 as the MSB

- Step 2: SAR: 1100 $\Rightarrow V_{DAC} = 12 \cdot V_{LSB} = 2.25V$

$V_{in} < V_{DAC} \Rightarrow$ bit 2 is 0

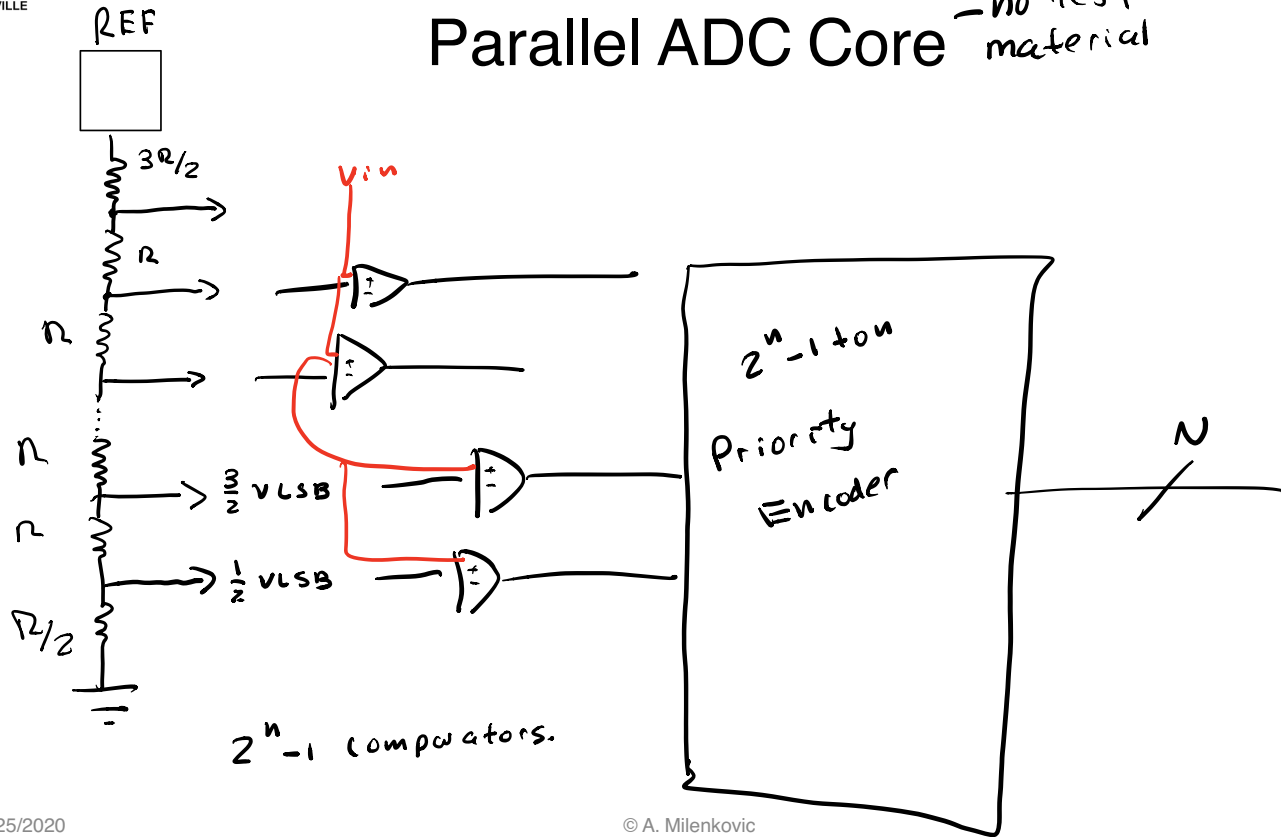
- Step 3: SAR: 1010 $\Rightarrow V_{DAC} = 10 \cdot V_{LSB} = 1.875V$

$V_{in} < V_{DAC}$, Bit 1 is 0

- Step 4: SAR: 1001 $\Rightarrow V_{DAC} = 9 \cdot V_{LSB} = 1.6875V$

$V_{in} > V_{DAC}$ Bit 0 is 1

Parallel ADC Core - no test material

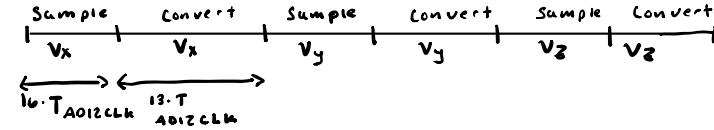


MSP430 ADC12 — A

V_x

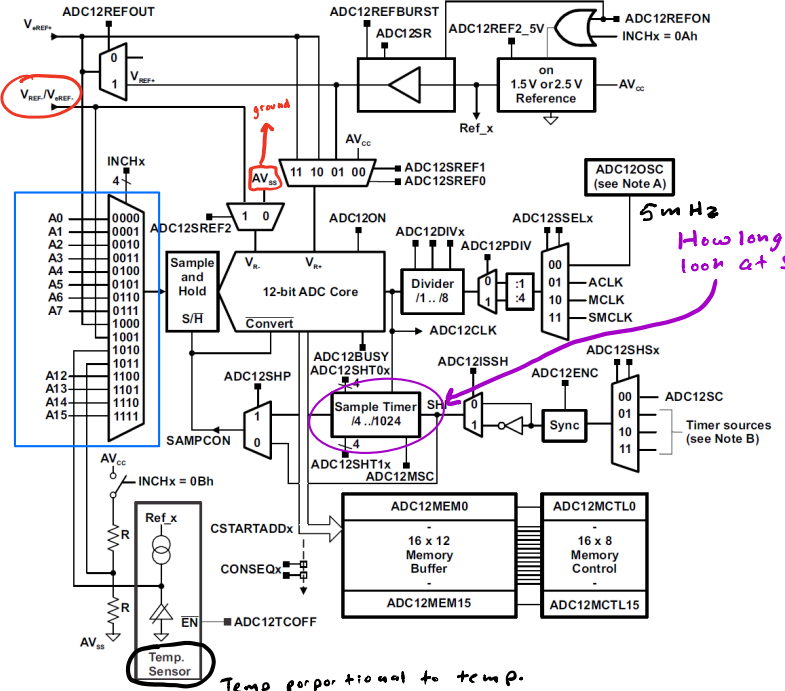
V_y

V_z



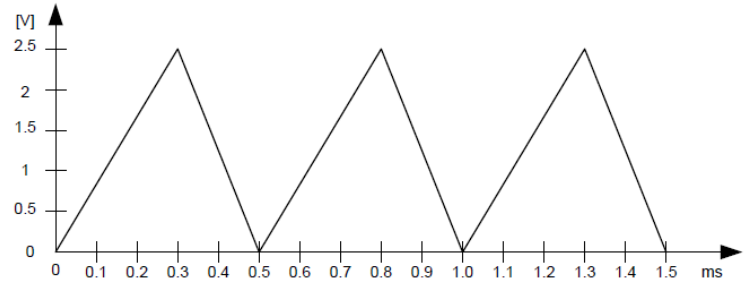
External signal

Input multiplexer



Walk Through

- $F_s = 10,000$ Hz (sampling rate)
- $T_s =$
- $V_{min} =$
- $V_{max} =$
- Find samples for one period



Measuring Temperature

(on-chip temperature sensor on MSP430F5529)

- Input channel INCHx=1010 (10)
- Temperature sensor equations
- Sample time > 30 μ s
- Calibration may be needed
- TCsensor – slope (mV/ $^{\circ}$ C),
- Vsensor – intercept (mV)

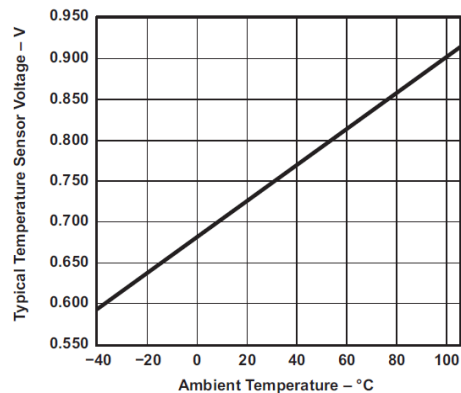


Figure 28-11. Typical Temperature Sensor Transfer Function

+ 30

Demo

Demo (cont'd)

